

PACKAGE/ORDERING INFORMATION

| PRODUCT | PACKAGE LEAD | PACKAGE DESIGNATOR | SPECIFIED TEMPERATURE RANGE | PACKAGE MARKING | ORDERING NUMBER | TRANSPORT MEDIA, QUANTITY |
|---------|-------------------------------------|--------------------|-----------------------------|-----------------|-----------------|---------------------------|
| ADS5411 | HTQFP-52 ⁽¹⁾ PowerPAD | PJY | –40°C to +85°C | ADS5411I | ADS5411IPJY | Tray, 160 |
| | | | | | ADS5411IPJYR | Tape and Reel, 1000 |

(1) Thermal pad size: Octagonal 2,5 mm side

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted⁽¹⁾

| | | ADS5411 | UNIT |
|--------------------------------|--------------------------|---------------------------------|------|
| Supply voltage | AV _{DD} to GND | 6 | V |
| | DRV _{DD} to GND | 5 | |
| Analog input to GND | | –0.3 to AV _{DD} + 0.3 | V |
| Clock input to GND | | –0.3 to AV _{DD} + 0.3 | V |
| CLK to $\overline{\text{CLK}}$ | | ±2.5 | V |
| Digital data output to GND | | –0.3 to DRV _{DD} + 0.3 | V |
| Operating temperature range | | –40 to 85 | °C |
| Maximum junction temperature | | 150 | °C |
| Storage temperature range | | –65 to 150 | °C |

(1) Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not implied.

THERMAL CHARACTERISTICS⁽¹⁾

| PARAMETER | TEST CONDITIONS | TYP | UNIT |
|---------------|-----------------------------------|------|------|
| θ_{JA} | Soldered slug, no airflow | 22.5 | °C/W |
| θ_{JA} | Soldered slug, 200-LPFM airflow | 15.8 | °C/W |
| θ_{JA} | Unsoldered slug, no airflow | 33.3 | °C/W |
| θ_{JA} | Unsoldered slug, 200-LPFM airflow | 25.9 | °C/W |
| θ_{JC} | Bottom of package (heatslug) | 2 | °C/W |

(1) Using 25 thermal vias (5 x 5 array). See the Application Section.



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because small parametric changes could cause the device not to meet its published specifications.

RECOMMENDED OPERATING CONDITIONS

| PARAMETER | MIN | TYP | MAX | UNIT |
|--|------|-----|------|-----------------|
| Supplies | | | | |
| Analog supply voltage, AV _{DD} | 4.75 | 5 | 5.25 | V |
| Output driver supply voltage, DRV _{DD} | 3 | 3.3 | 3.6 | V |
| Analog Input | | | | |
| Differential input range | | 2.2 | | V _{PP} |
| Input common-mode voltage, V _{CM} | | 2.4 | | V |
| Digital Output | | | | |
| Maximum output load | | 10 | | pF |
| Clock Input | | | | |
| ADCLK input sample rate (sine wave) 1/t _C | 30 | | 105 | MSPS |
| Clock amplitude, sine wave, differential | 1 | 3 | 5 | V _{PP} |
| Clock duty cycle | 40% | 50% | 60% | |
| Open free-air temperature range | –40 | | 85 | °C |

ELECTRICAL CHARACTERISTICS

Over full temperature range ($T_{MIN} = -40^{\circ}\text{C}$ to $T_{MAX} = 85^{\circ}\text{C}$), sampling rate = 105 MSPS, 50% clock duty cycle, $AV_{DD} = 5\text{ V}$, $DRV_{DD} = 3.3\text{ V}$, -1 dBFS differential input, and 3 V_{PP} differential sinusoidal clock, unless otherwise noted

| PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---|--|------|------------|-----|-------------------------|
| Resolution | | | 11 | | Bits |
| Analog Inputs | | | | | |
| Differential input range | | | 2.2 | | V_{PP} |
| Differential input resistance | See Figure 2 | | 1 | | $k\Omega$ |
| Differential input capacitance | See Figure 2 | | 1.5 | | pF |
| Analog input bandwidth | | | 570 | | MHz |
| Internal Reference Voltages | | | | | |
| Reference voltage, V_{REF} | | | 2.4 | | V |
| Dynamic Accuracy | | | | | |
| No missing codes | | | Tested | | |
| Differential linearity error, DNL | $f_{IN} = 10\text{ MHz}$ | -0.5 | ± 0.25 | 0.5 | LSB |
| Integral linearity error, INL | $f_{IN} = 10\text{ MHz}$ | -0.5 | ± 0.2 | 0.5 | LSB |
| Offset error | | -5 | 0 | 5 | mV |
| Offset temperature coefficient | | | 1.7 | | ppm/ $^{\circ}\text{C}$ |
| Gain error | | -5 | 0.9 | 5 | %FS |
| PSRR | | | 1 | | mV/V |
| Gain temperature coefficient | | | 77 | | ppm/ $^{\circ}\text{C}$ |
| Power Supply | | | | | |
| Analog supply current, I_{AVDD} | $V_{IN} = \text{full scale}, f_{IN} = 70\text{ MHz}$ | | 355 | 410 | mA |
| Output buffer supply current, I_{DRVDD} | $V_{IN} = \text{full scale}, f_{IN} = 70\text{ MHz}$ | | 35 | 47 | mA |
| Power dissipation | Total power with 10-pF load on each digital output to ground, $f_{IN} = 70\text{ MHz}$ | | 1.9 | 2.2 | W |
| Power-up time | | | 20 | 100 | ms |
| Dynamic AC Characteristics | | | | | |
| Signal-to-noise ratio, SNR | $f_{IN} = 10\text{ MHz}$ | | 66.5 | | dBc |
| | $f_{IN} = 30\text{ MHz}$ | 65.3 | 66.5 | | |
| | $f_{IN} = 50\text{ MHz}$ | | 66.4 | | |
| | $f_{IN} = 70\text{ MHz}$ | 65.3 | 66.3 | | |
| | $f_{IN} = 100\text{ MHz}$ | | 65.9 | | |
| | $f_{IN} = 170\text{ MHz}$ | | 65.7 | | |
| | $f_{IN} = 230\text{ MHz}$ | | 65.4 | | |
| Spurious-free dynamic range, SFDR | $f_{IN} = 10\text{ MHz}$ | | 91 | | dBc |
| | $f_{IN} = 30\text{ MHz}$ | 85 | 91 | | |
| | $f_{IN} = 50\text{ MHz}$ | | 90 | | |
| | $f_{IN} = 70\text{ MHz}$ | | 90 | | |
| | $f_{IN} = 100\text{ MHz}$ | | 89 | | |
| | $f_{IN} = 170\text{ MHz}$ | | 81 | | |
| | $f_{IN} = 230\text{ MHz}$ | | 71 | | |

ELECTRICAL CHARACTERISTICS

Over full temperature range ($T_{MIN} = -40^{\circ}\text{C}$ to $T_{MAX} = 85^{\circ}\text{C}$), sampling rate = 105 MSPS, 50% clock duty cycle, $AV_{DD} = 5\text{ V}$, $DRV_{DD} = 3.3\text{ V}$, -1 dBFS differential input, and 3 V_{PP} differential sinusoidal clock, unless otherwise noted

| PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--|---------------------------|-----|------|-----|------|
| Signal-to-noise + distortion, SINAD | $f_{IN} = 10\text{ MHz}$ | | 66.5 | | dBc |
| | $f_{IN} = 30\text{ MHz}$ | 65 | 66.5 | | |
| | $f_{IN} = 50\text{ MHz}$ | | 66.3 | | |
| | $f_{IN} = 70\text{ MHz}$ | 65 | 66 | | |
| | $f_{IN} = 100\text{ MHz}$ | | 65.9 | | |
| | $f_{IN} = 170\text{ MHz}$ | | 65.4 | | |
| | $f_{IN} = 230\text{ MHz}$ | | 63.6 | | |
| Second harmonic, HD2 | $f_{IN} = 10\text{ MHz}$ | | 100 | | dBc |
| | $f_{IN} = 30\text{ MHz}$ | | 100 | | |
| | $f_{IN} = 50\text{ MHz}$ | | 98 | | |
| | $f_{IN} = 70\text{ MHz}$ | | 96 | | |
| | $f_{IN} = 100\text{ MHz}$ | | 91 | | |
| | $f_{IN} = 170\text{ MHz}$ | | 87 | | |
| | $f_{IN} = 230\text{ MHz}$ | | 87 | | |
| Third harmonic, HD3 | $f_{IN} = 10\text{ MHz}$ | | 91 | | dBc |
| | $f_{IN} = 30\text{ MHz}$ | | 91 | | |
| | $f_{IN} = 50\text{ MHz}$ | | 90 | | |
| | $f_{IN} = 70\text{ MHz}$ | | 90 | | |
| | $f_{IN} = 100\text{ MHz}$ | | 89 | | |
| | $f_{IN} = 170\text{ MHz}$ | | 81 | | |
| | $f_{IN} = 230\text{ MHz}$ | | 71 | | |
| Worst-harmonic / spur (other than HD2 and HD3) | $f_{IN} = 10\text{ MHz}$ | | 94 | | dBc |
| | $f_{IN} = 30\text{ MHz}$ | | 95 | | |
| | $f_{IN} = 50\text{ MHz}$ | | 95 | | |
| | $f_{IN} = 70\text{ MHz}$ | | 90 | | |
| | $f_{IN} = 100\text{ MHz}$ | | 89 | | |
| | $f_{IN} = 170\text{ MHz}$ | | 88 | | |
| | $f_{IN} = 230\text{ MHz}$ | | 88 | | |
| RMS idle channel noise | Input pins tied together | | 0.3 | | LSB |

DIGITAL CHARACTERISTICS

Over full temperature range ($T_{MIN} = -40^{\circ}\text{C}$ to $T_{MAX} = 85^{\circ}\text{C}$), $AV_{DD} = 5\text{ V}$, $DRV_{DD} = 3.3\text{ V}$, unless otherwise noted

| PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------|---------------------------------|-----|--------------|-----|------|
| Digital Outputs | | | | | |
| Low-level output voltage | $C_{LOAD} = 10\text{ pF}^{(1)}$ | | 0.1 | 0.6 | V |
| High-level output voltage | $C_{LOAD} = 10\text{ pF}^{(1)}$ | 2.6 | 3.2 | | V |
| Output capacitance | | | 3 | | pF |
| DMID | | | $DRV_{DD}/2$ | | V |

⁽¹⁾ Equivalent capacitance to ground of (load + parasitics of transmission lines).

TIMING CHARACTERISTICS⁽³⁾

Over full temperature range, $AV_{DD} = 5\text{ V}$, $DRV_{DD} = 3.3\text{ V}$, sampling rate = 105 MSPS

| PARAMETER | DESCRIPTION | MIN | TYP | MAX | UNIT |
|---|---|-----|---------------------|-----|---------------|
| Aperture Time | | | | | |
| t_A | Aperture delay | | 500 | | ps |
| t_J | Clock slope independent aperture uncertainty (jitter) | | 150 | | fs |
| k_J | Clock slope dependent jitter factor | | 50 | | μV |
| Clock Input | | | | | |
| t_{CLK} | Clock period | | 9.5 | | ns |
| $t_{CLKH}^{(1)}$ | Clock pulse width high | | 4.75 | | ns |
| $t_{CLKL}^{(1)}$ | Clock pulse width low | | 4.75 | | ns |
| Clock to DataReady (DRY) | | | | | |
| t_{DR} | Clock rising 50% to DRY falling 50% | 2.8 | 3.9 | 4.7 | ns |
| t_{C_DR} | Clock rising 50% to DRY rising 50% | | $t_{DR} + t_{CLKH}$ | | ns |
| $t_{C_DR_50\%}$ | Clock rising 50% to DRY rising 50% with 50% duty cycle clock | 7.6 | 8.7 | 9.5 | ns |
| Clock to DATA, OVR⁽⁴⁾ | | | | | |
| t_r | Data V_{OL} to data V_{OH} (rise time) | | 2 | | ns |
| t_f | Data V_{OH} to data V_{OL} (fall time) | | 2 | | ns |
| L | Latency | | 3 | | Cycles |
| $t_{su(C)}$ | Valid DATA ⁽²⁾ to clock 50% with 50% duty cycle clock (setup time) | 1.8 | 3.4 | | ns |
| $t_{h(C)}$ | Clock 50% to invalid DATA ⁽²⁾ (hold time) | 2.6 | 3.6 | | ns |
| DataReady (DRY) to DATA, OVR⁽⁴⁾ | | | | | |
| $t_{su(DR) 50\%}$ | Valid DATA ⁽²⁾ to DRY 50% with 50% duty cycle clock (setup time) | 1.6 | 2.6 | | ns |
| $t_{h(DR) 50\%}$ | DRY 50% to invalid DATA ⁽²⁾ with 50% duty cycle clock (hold time) | 3.9 | 4.4 | | ns |

(1) See Figure 1 for more information.

(2) See V_{OH} and V_{OL} levels.

(3) All values obtained from design and characterization.

(4) Data is updated with clock rising edge or DRY falling edge.

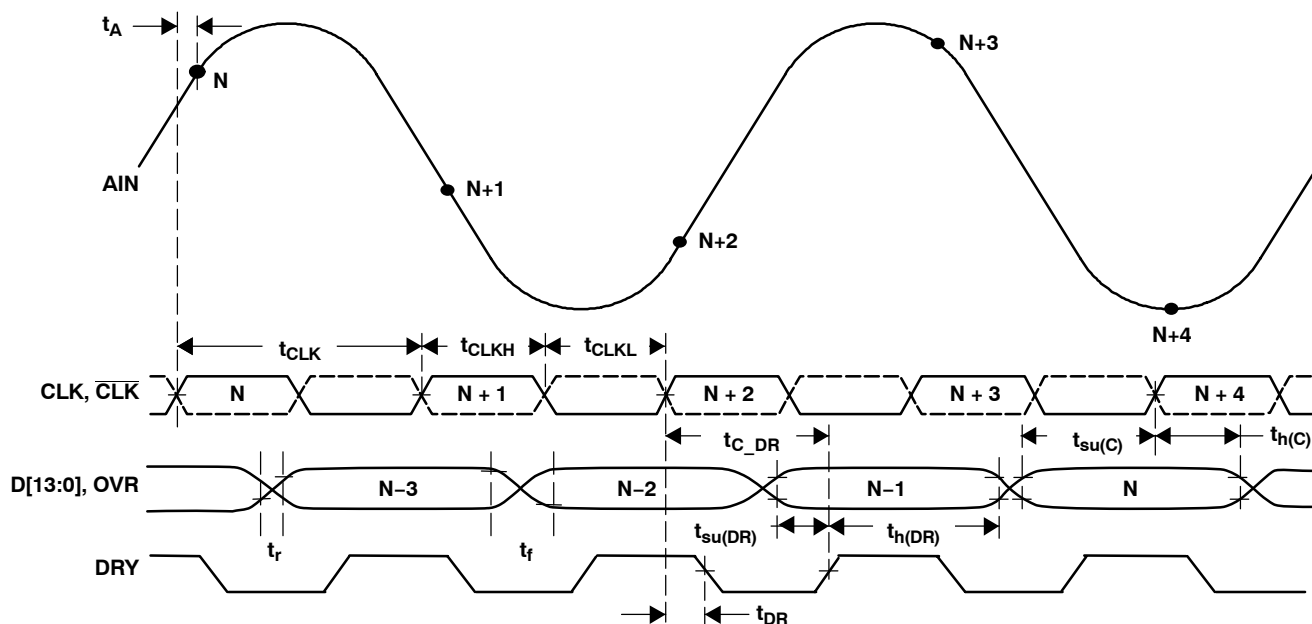
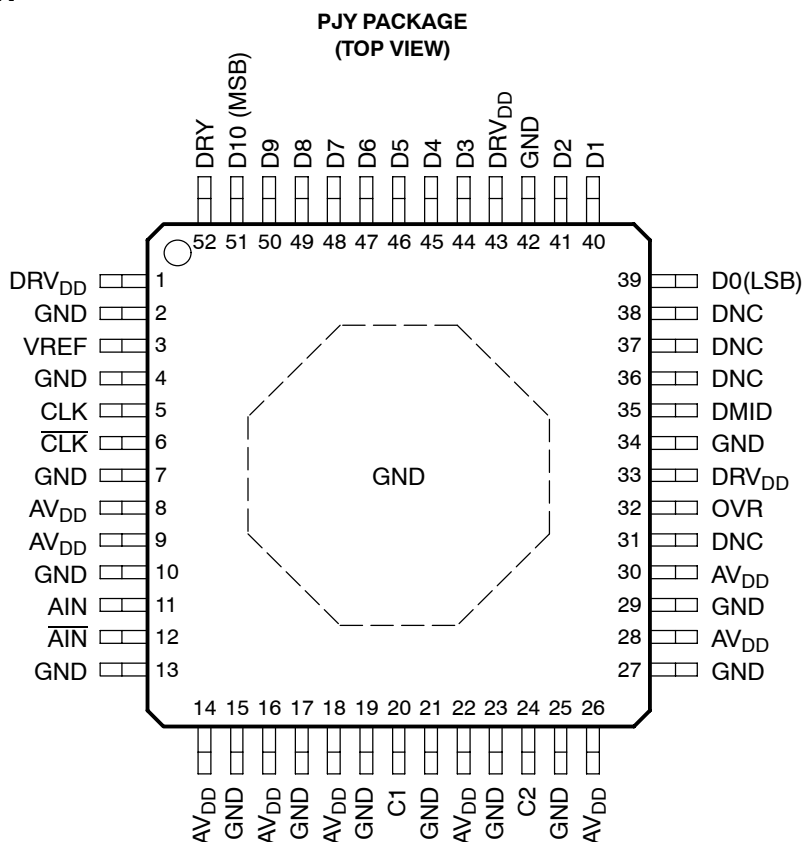


Figure 1. Timing Diagram

PIN CONFIGURATION



PIN ASSIGNMENTS

| TERMINAL | | DESCRIPTION |
|-------------------|---|--|
| NAME | NO. | |
| DRV _{DD} | 1, 33, 43 | 3.3 V power supply, digital output stage only |
| GND | 2, 4, 7, 10, 13, 15, 17, 19, 21, 23, 25, 27, 29, 34, 42 | Ground |
| VREF | 3 | 2.4 V reference. Bypass to ground with a 0.1-μF microwave chip capacitor. |
| CLK | 5 | Clock input. Conversion initiated on rising edge. |
| CLK | 6 | Complement of CLK, differential input |
| AV _{DD} | 8, 9, 14, 16, 18, 22, 26, 28, 30 | 5 V analog power supply |
| AIN | 11 | Analog input |
| AIN | 12 | Complement of AIN, differential analog input |
| C1 | 20 | Internal voltage reference. Bypass to ground with a 0.1-μF chip capacitor. |
| C2 | 24 | Internal voltage reference. Bypass to ground with a 0.1-μF chip capacitor. |
| DNC | 31, 36, 37, 38 | Do not connect |
| OVR | 32 | Overrange bit. A logic level high indicates the analog input exceeds full scale. |
| DMID | 35 | Output data voltage midpoint. Approximately equal to (DRV _{DD})/2 |
| D0 (LSB) | 39 | Digital output bit (least significant bit); two's complement |
| D1, D2, D3–D9 | 40, 41, 44–50 | Digital output bits in two's complement |
| D10 (MSB) | 51 | Digital output bit (most significant bit); two's complement |
| DRY | 52 | Data ready output |

DEFINITION OF SPECIFICATIONS

Analog Bandwidth

The analog input frequency at which the power of the fundamental is reduced by 3 dB with respect to the low frequency value.

Aperture Delay

The delay in time between the rising edge of the input sampling clock and the actual time at which the sampling occurs.

Aperture Uncertainty (Jitter)

The sample-to-sample variation in aperture delay.

Clock Pulse Width/Duty Cycle

The duty cycle of a clock signal is the ratio of the time the clock signal remains at a logic high (clock pulse width) to the period of the clock signal. Duty cycle is typically expressed as a percentage. A perfect differential sine wave clock results in a 50% duty cycle.

Maximum Conversion Rate

The maximum sampling rate at which certified operation is given. All parametric testing is performed at this sampling rate unless otherwise noted.

Minimum Conversion Rate

The minimum sampling rate at which the ADC functions.

Differential Nonlinearity (DNL)

An ideal ADC exhibits code transitions at analog input values spaced exactly 1 LSB apart. The DNL is the deviation of any single step from this ideal value, measured in units of LSB.

Integral Nonlinearity (INL)

The INL is the deviation of the ADC's transfer function from a best fit line determined by a least squares curve fit of that transfer function, measured in units of LSB.

Gain Error

The gain error is the deviation of the ADC's actual input full-scale range from its ideal value. The gain error is given as a percentage of the ideal input full-scale range.

Offset Error

The offset error is the difference, given in number of LSBs, between the ADC's actual value average idle channel output code and the ideal average idle channel output code. This quantity is often mapped into mV.

PSRR

The maximum change in offset voltage divided by the total change in supply voltage, in units of mV/V.

Temperature Drift

The temperature drift coefficient (with respect to gain error and offset error) specifies the change per degree Celsius of the parameter from T_{MIN} or T_{MAX} . It is computed as the maximum variation of that parameter over the whole temperature range divided by $T_{MAX} - T_{MIN}$.

Signal-to-Noise Ratio (SNR)

SNR is the ratio of the power of the fundamental (P_S) to the noise floor power (P_N), excluding the power at dc and the first five harmonics.

$$SNR = 10\log_{10} \frac{P_S}{P_N}$$

SNR is either given in units of dBc (dB to carrier) when the absolute power of the fundamental is used as the reference or dBFS (dB to full scale) when the power of the fundamental is extrapolated to the converter's full-scale range.

Signal-to-Noise and Distortion (SINAD)

SINAD is the ratio of the power of the fundamental (P_S) to the power of all the other spectral components including noise (P_N) and distortion (P_D), but excluding dc.

$$SINAD = 10\log_{10} \frac{P_S}{P_N + P_D}$$

SINAD is either given in units of dBc (dB to carrier) when the absolute power of the fundamental is used as the reference or dBFS (dB to full scale) when the power of the fundamental is extrapolated to the converter's full-scale range.

Total Harmonic Distortion (THD)

THD is the ratio of the fundamental power (P_S) to the power of the first five harmonics (P_D).

$$THD = 10\log_{10} \frac{P_S}{P_D}$$

THD is typically given in units of dBc (dB to carrier).

Power Up Time

The difference in time from the point where the supplies are stable at $\pm 5\%$ of the final value, to the time the ac test is past.

Spurious-Free Dynamic Range (SFDR)

The ratio of the power of the fundamental to the highest other spectral component (either spur or harmonic). SFDR is typically given in units of dBc (dB to carrier).

Two-Tone Intermodulation Distortion

IMD3 is the ratio of the power of the fundamental (at frequencies f_1 , f_2) to the power of the worst spectral component at either frequency $2f_1 - f_2$ or $2f_2 - f_1$). IMD3 is either given in units of dBc (dB to carrier) when the absolute power of the fundamental is used as the reference or dBFS (dB to full scale) when it is referred to the full-scale range.

EQUIVALENT CIRCUITS

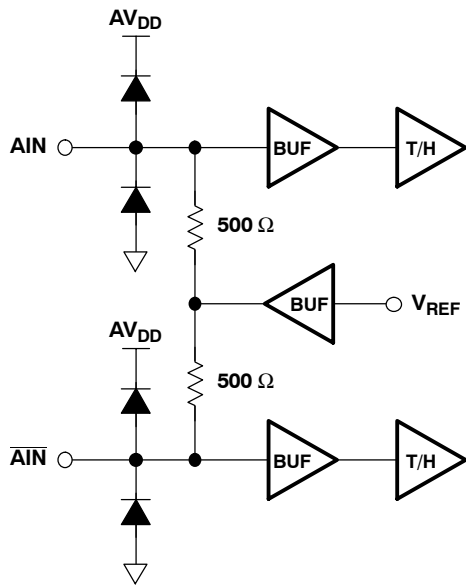


Figure 2. Analog Input

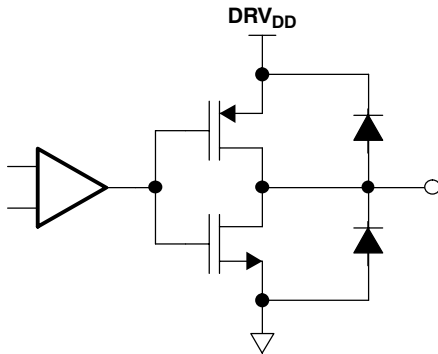


Figure 3. Digital Output

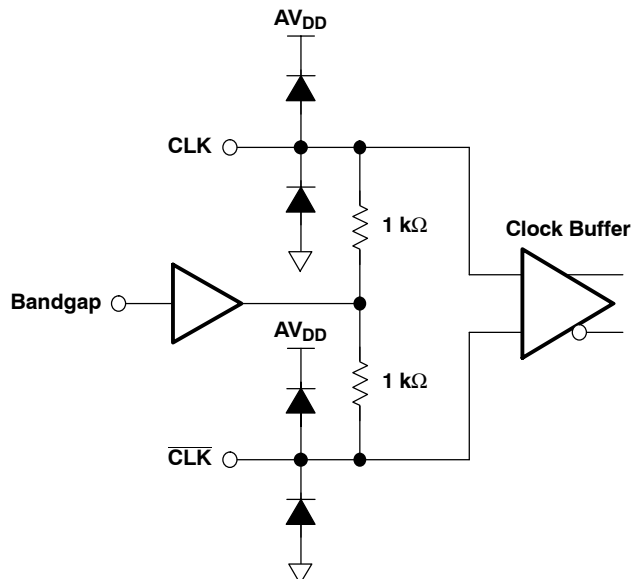


Figure 4. Clock Input

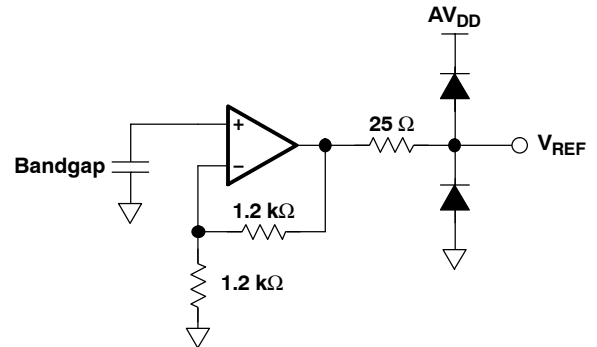


Figure 5. Reference

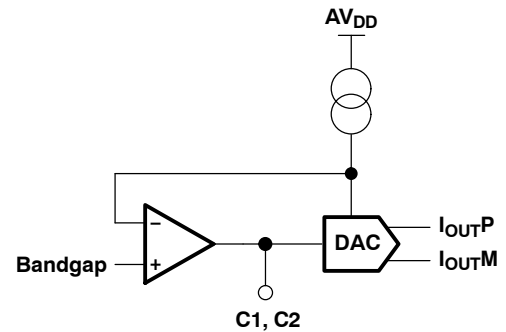


Figure 6. Decoupling Pin

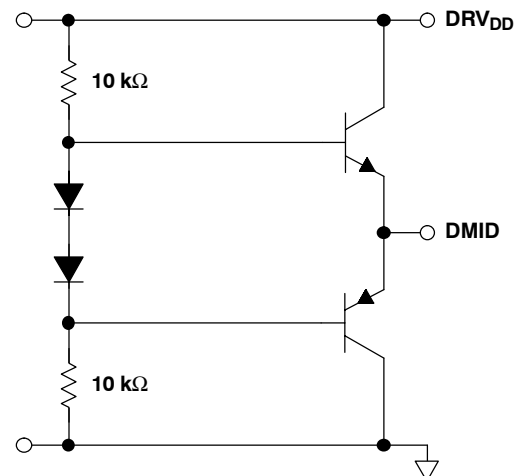


Figure 7. DMID Generation

TYPICAL CHARACTERISTICS

Typical values are at $T_A = 25^\circ\text{C}$, $AVDD = 5\text{ V}$, $DRVDD = 3.3\text{ V}$, differential input amplitude = -1 dBFS , sampling rate = 105 MSPS , 3 V_{PP} sinusoidal clock, 50% duty cycle, 8k FFT points, unless otherwise noted

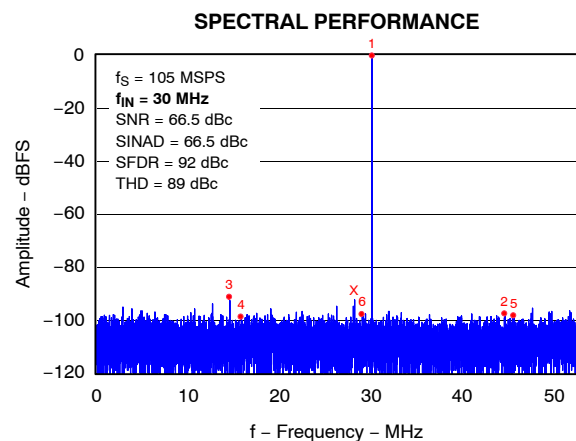


Figure 8.

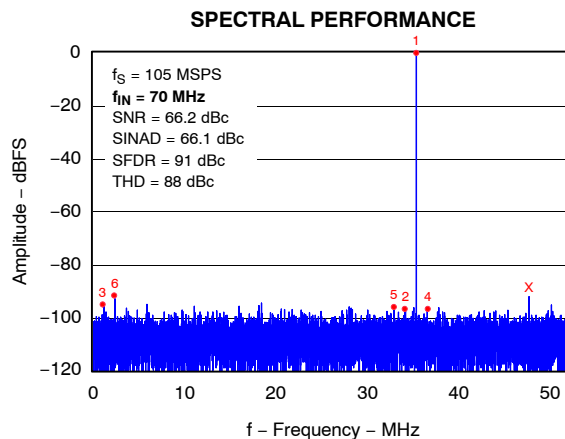


Figure 9.

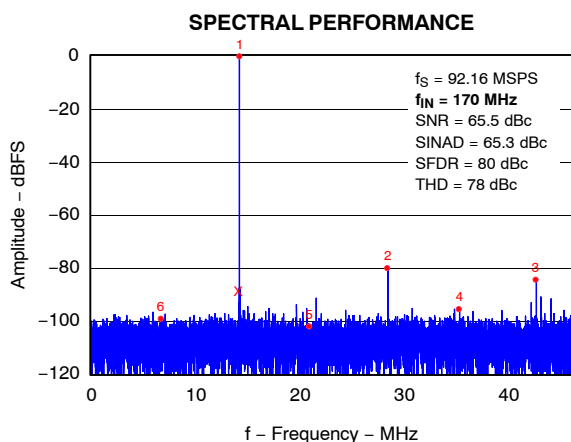


Figure 10.

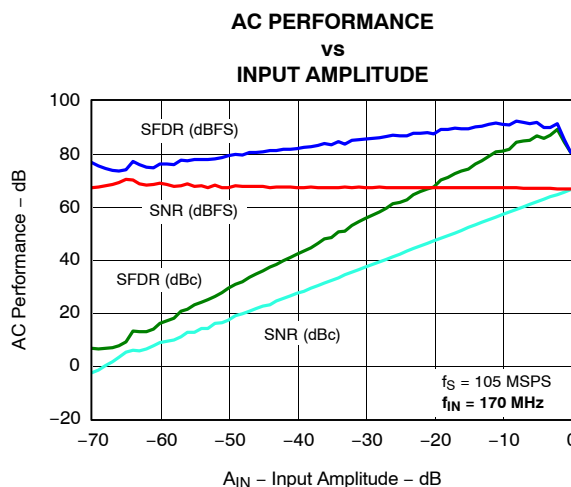


Figure 11.

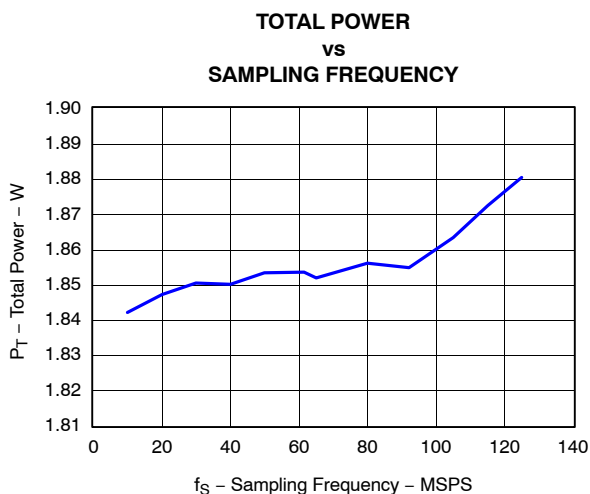


Figure 12.

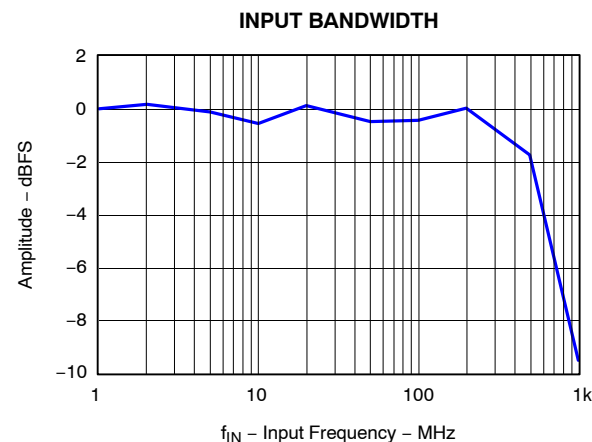


Figure 13.

TYPICAL CHARACTERISTICS

Typical values are at $T_A = 25^\circ\text{C}$, $AV_{DD} = 5\text{ V}$, $DRV_{DD} = 3.3\text{ V}$, differential input amplitude = -1 dBFS , sampling rate = 105 MSPS , 3 V_{PP} sinusoidal clock, 50% duty cycle, 8k FFT points, unless otherwise noted

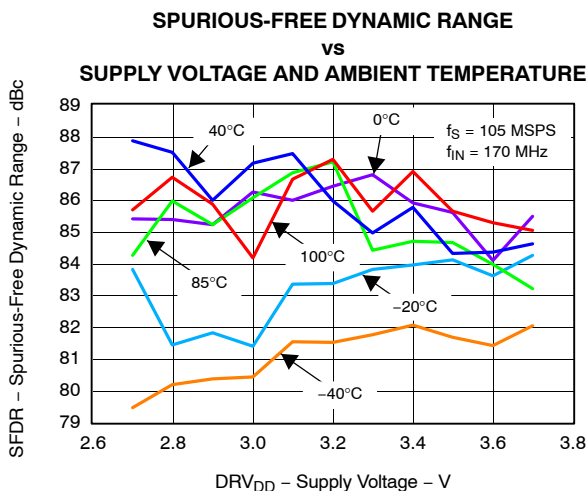


Figure 14.

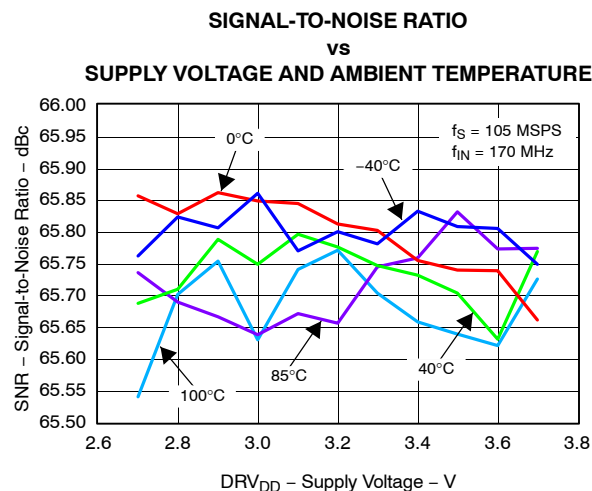


Figure 15.

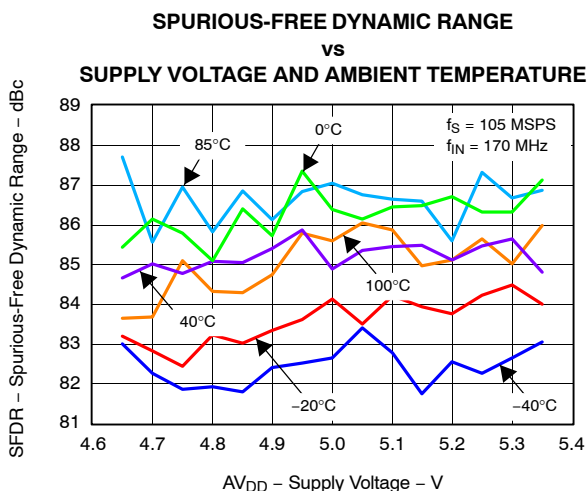


Figure 16.

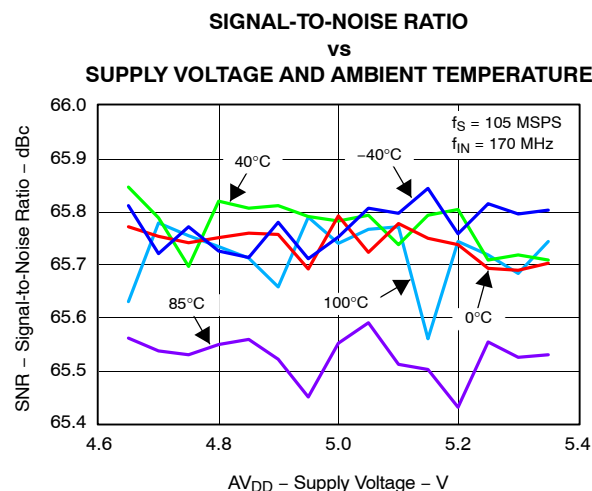


Figure 17.

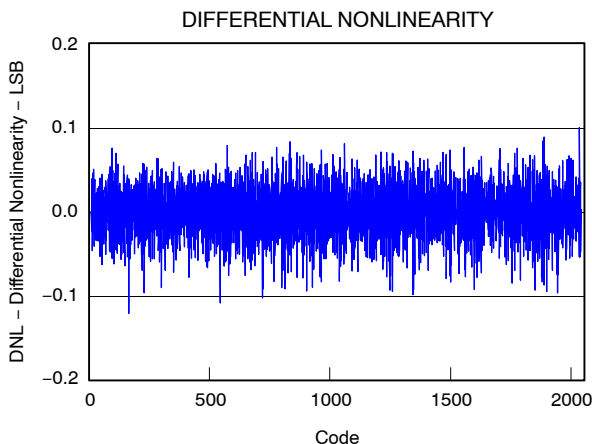


Figure 18.

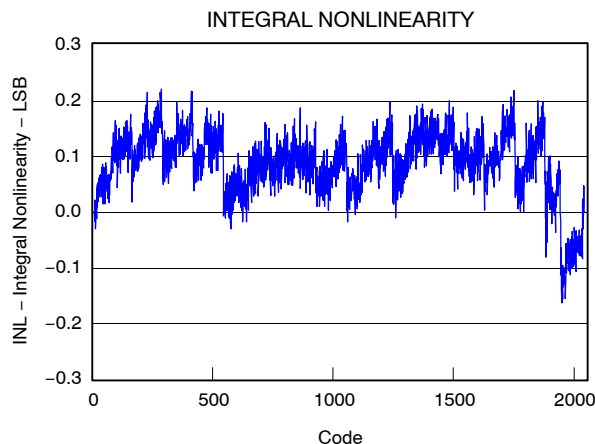


Figure 19.

TYPICAL CHARACTERISTICS

Typical values are at $T_A = 25^\circ\text{C}$, $AVDD = 5\text{ V}$, $DRVDD = 3.3\text{ V}$, differential input amplitude = -1 dBFS , sampling rate = 105 MSPS , 3 V_{PP} sinusoidal clock, 50% duty cycle, 8k FFT points, unless otherwise noted

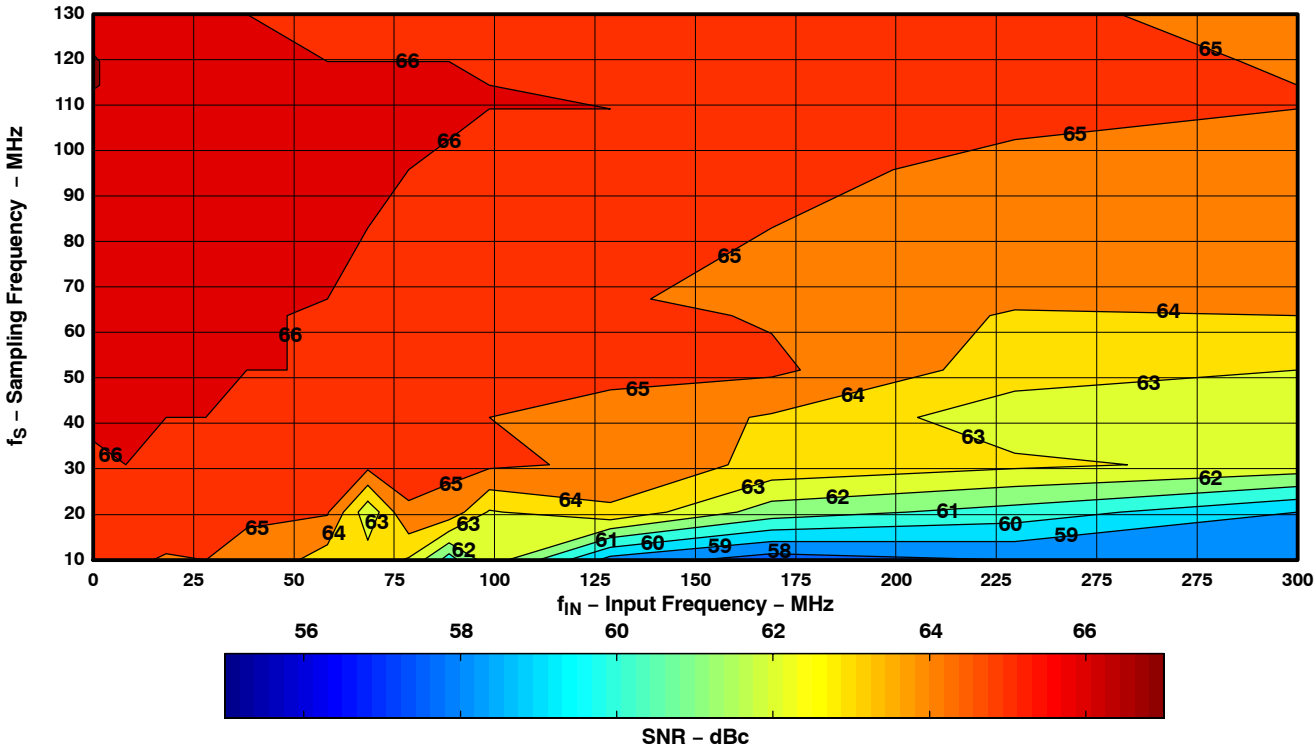


Figure 20.

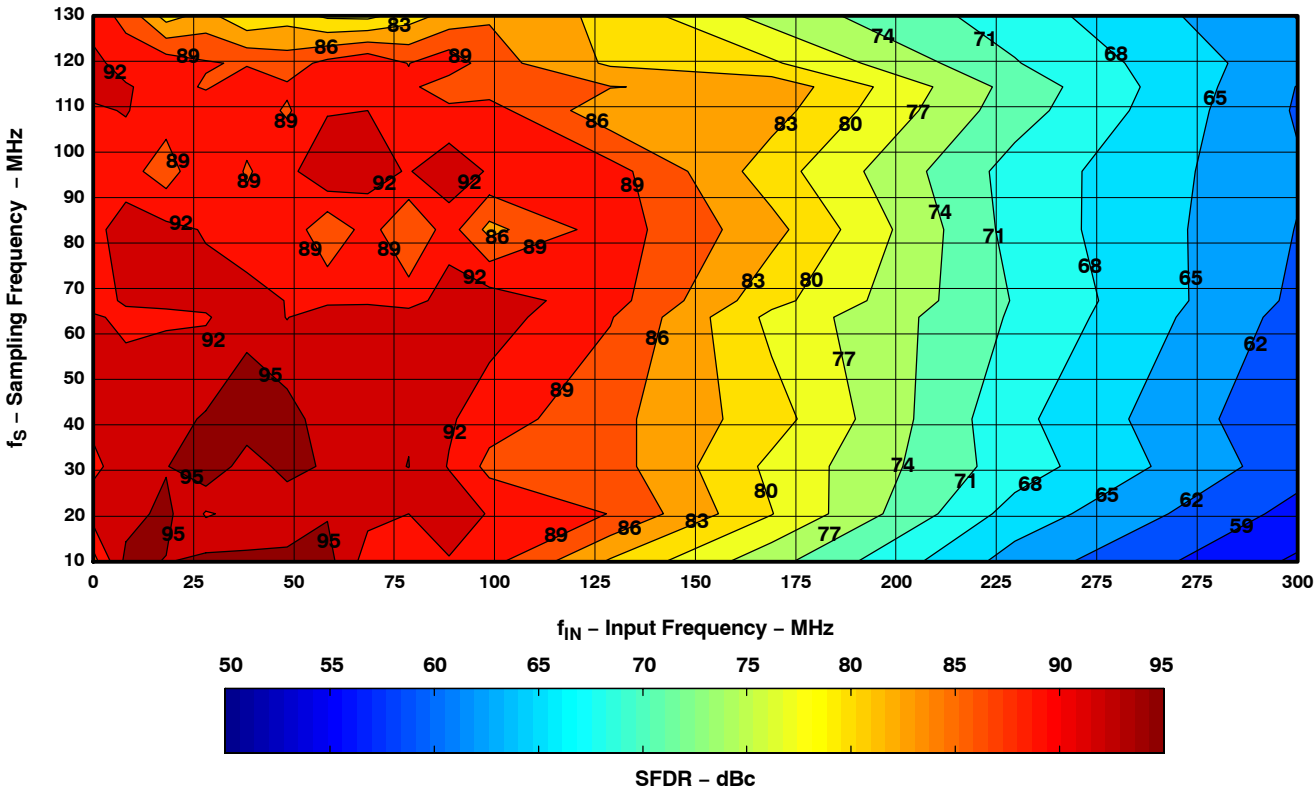


Figure 21.

APPLICATION INFORMATION

THEORY OF OPERATION

The ADS5411 is a 11 bit, 105 MSPS, monolithic pipeline analog to digital converter. Its bipolar analog core operates from a 5 V supply, while the output uses 3.3 V supply for compatibility with the CMOS family. The conversion process is initiated by the rising edge of the external input clock. At that instant, the differential input signal is captured by the input track and hold (T&H) and the input sample is sequentially converted by a series of small resolution stages, with the outputs combined in a digital correction logic block. Both the rising and the falling clock edges are used to propagate the sample through the pipeline every half clock cycle. This process results in a data latency of three clock cycles, after which the output data is available as a 11 bit parallel word, coded in binary two's complement format.

INPUT CONFIGURATION

The analog input for the ADS5411 (see Figure 2) consists of an analog differential buffer followed by a bipolar track-and-hold. The analog buffer isolates the source driving the input of the ADC from any internal switching. The input common mode is set internally through a $500\ \Omega$ resistor connected from 2.4 V to each of the inputs. This results in a differential input impedance of $1\ \text{k}\Omega$.

For a full-scale differential input, each of the differential lines of the input signal (pins 11 and 12) swings symmetrically between $2.4 + 0.55 \text{ V}$ and $2.4 - 0.55 \text{ V}$. This means that each input is driven with a signal of up to $2.4 \pm 0.55 \text{ V}$, so that each input has a maximum signal swing of $1.1 \text{ V}_{\text{PP}}$ for a total differential input signal swing

of 2.2 V_{PP}. The maximum swing is determined by the internal reference voltage generator eliminating any external circuitry for this purpose.

The ADS5411 obtains optimum performance when the analog inputs are driven differentially. The circuit in Figure 22 shows one possible configuration using an RF transformer with termination either on the primary or on the secondary of the transformer. If voltage gain is required a step up transformer can be used. For higher gains that would require impractical higher turn ratios on the transformer, a single-ended amplifier driving the transformer can be used (see Figure 23). Another circuit optimized for performance would be the one on Figure 24, using the THS4304 or the OPA695. Texas Instruments has shown excellent performance on this configuration up to 10 dB gain with the THS4304 and at 14 dB gain with the OPA695. For the best performance, they need to be configured differentially after the transformer (as shown) or in inverting mode for the OPA695 (see SBAA113); otherwise, HD2 from the op amps limits the useful frequency.

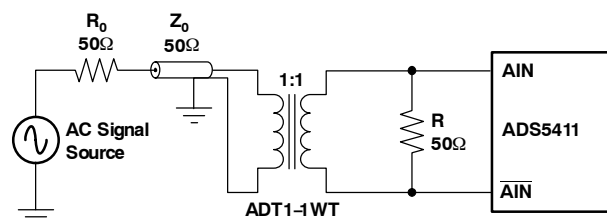


Figure 22. Converting a Single-Ended Input to a Differential Signal Using RF Transformers

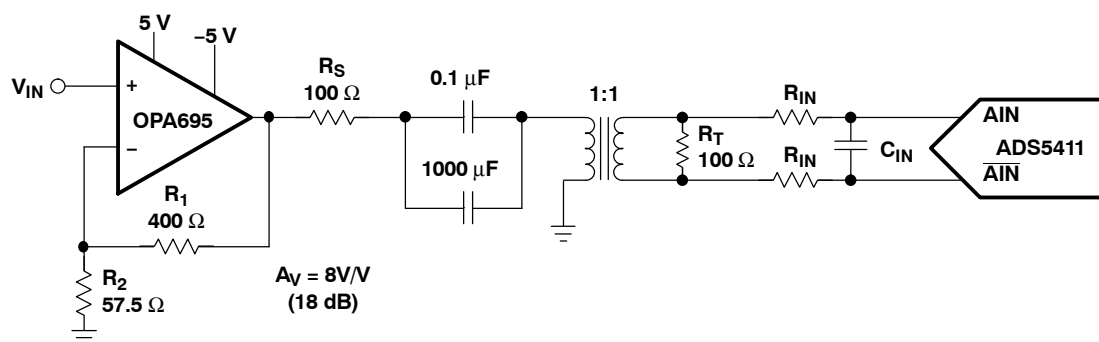


Figure 23. Using the OPA695 With the ADS5411

APPLICATION INFORMATION

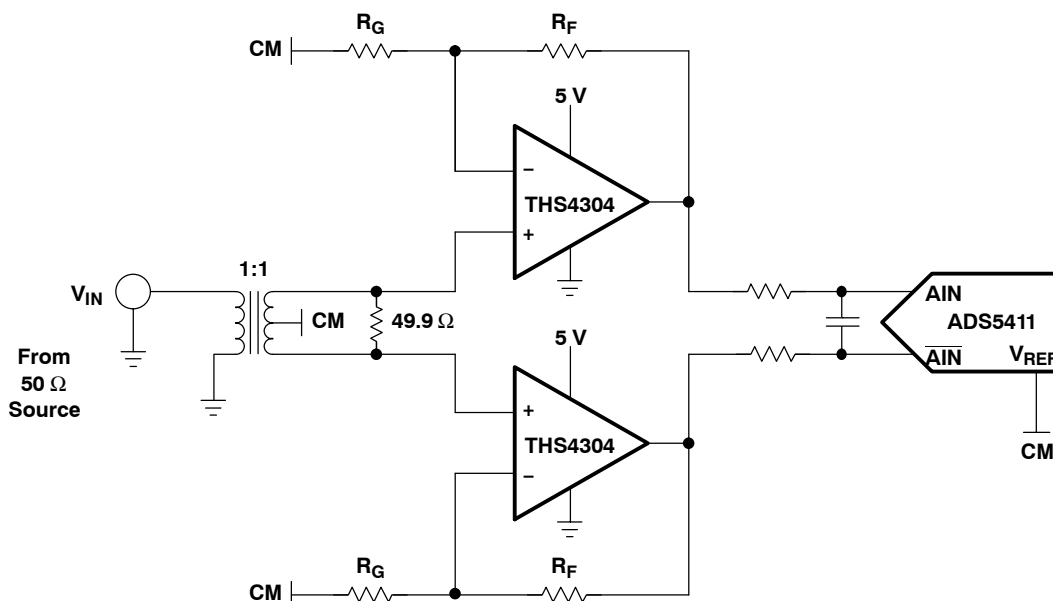


Figure 24. Using the THS4304 With the ADS5411

Besides these, Texas Instruments offers a wide selection of single-ended operational amplifiers (including the THS3201, THS3202, and OPA847) that can be selected depending on the application. An RF gain block amplifier, such as Texas Instrument's THS9001, can also be used with an RF transformer for high input frequency applications. For applications requiring dc-coupling with the signal source, instead of using a topology with three single ended amplifiers, a differential input/differential output amplifier like the THS4509 (see Figure 25) can be used, which minimizes board space and reduce number of components.

On this configuration, the THS4509 amplifier circuit provides 10 dB of gain, converts the single-ended input to differential, and sets the proper input common-mode voltage to the ADS5411.

The 225 Ω resistors and 2.7 pF capacitor between the THS4509 outputs and ADS5411 inputs (along with the input capacitance of the ADC) limit the bandwidth of the signal to about 100 MHz (–3 dB).

For this test, an Agilent signal generator is used for the signal source. The generator is an ac-coupled 50 Ω source. A band-pass filter is inserted in series with the input to reduce harmonics and noise from the signal source.

APPLICATION INFORMATION

Input termination is accomplished via the 69.8 Ω resistor and 0.22 μ F capacitor to ground in conjunction with the input impedance of the amplifier circuit. A 0.22 μ F capacitor and 49.9 Ω resistor is inserted to ground across the 69.8 Ω resistor and 0.22 μ F capacitor on the alternate input to balance the circuit.

Gain is a function of the source impedance, termination, and 348 Ω feedback resistor. See the THS4509 data sheet (SLOS454) for further component values to set proper 50 Ω termination for other common gains.

Since the ADS5411 recommended input common-mode voltage is 2.4 V, the THS4509 is operated from a single power supply input with $V_{S+} = 5$ V and $V_{S-} = 0$ V (ground). This maintains maximum headroom on the internal transistors of the THS4509.

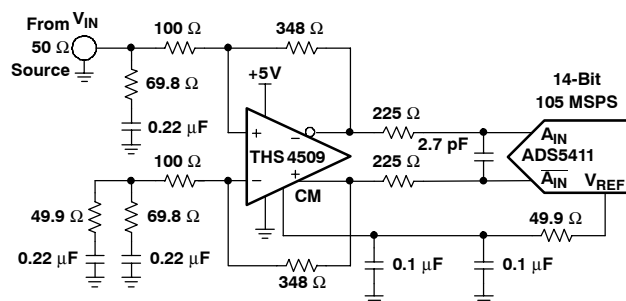


Figure 25. Using the THS4509 With the ADS5411

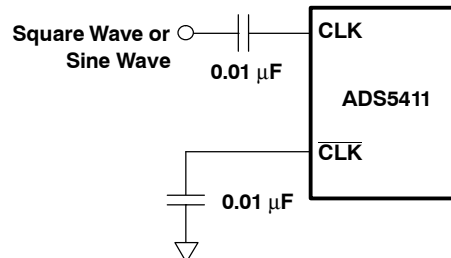


Figure 26. Single-Ended Clock

CLOCK INPUTS

The ADS5411 clock input can be driven with either a differential clock signal or a single-ended clock input, with little or no difference in performance between both configurations. In low input frequency applications, where jitter may not be a big concern, the use of single-ended clock (see Figure 26) could save some cost and board space without any trade-off in performance. When driven on this configuration, it is best to connect CLKM (pin 6) to ground with a 0.01 μ F capacitor, while CLKP is ac-coupled with a 0.01 μ F capacitor to the clock source, as shown in Figure 24.

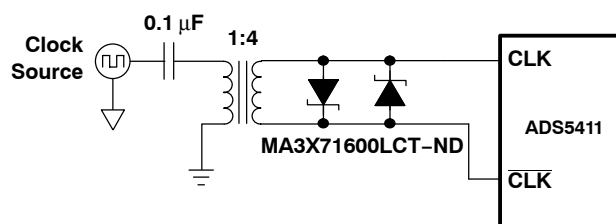


Figure 27. Differential Clock

Nevertheless, for jitter sensitive applications, the use of a differential clock will have some advantages (as with any other ADCs) at the system level. The first advantage is that it allows for common-mode noise rejection at the PCB level. A further analysis (see *Clocking High Speed Data Converters*, SLYT075) reveals one more advantage. The following formula describes the different contributions to clock jitter:

$$(\text{Jitter}_{\text{total}})^2 = (\text{EXT_jitter})^2 + (\text{ADC_jitter})^2 + (\text{EXT_jitter})^2 + (\text{ADC_int})^2 + (\text{K/clock_slope})^2$$

APPLICATION INFORMATION

The first term would represent the external jitter, coming from the clock source, plus noise added by the system on the clock distribution, up to the ADC. The second term is the ADC contribution, which can be divided in two portions. The first does not depend directly on any external factor. That is the best we can get out of our ADC. The second contribution is a term inversely proportional to the clock slope. The faster the slope, the smaller this term will be. As an example, we could compute the ADC jitter contribution from a sinusoidal input clock of 3 V_{pp} amplitude and F_s = 80 MSPS:

$$\text{ADC_jitter} = \sqrt{((150\text{fs})^2 + (5 \times 10^{-5}) / (1.5 \times 2 \times \text{PI} \times 80 \times 10^6))^2} = 164\text{fs}$$

The use of differential clock allows for the use of bigger clock amplitudes without exceeding the absolute maximum ratings. This, on the case of sinusoidal clock, results on higher slew rates which minimizes the impact of the jitter factor inversely proportional to the clock slope.

Figure 27 shows this approach. The back-to-back Schottky can be added to limit the clock amplitude in cases where this would exceed the absolute maximum ratings, even when using a differential clock.

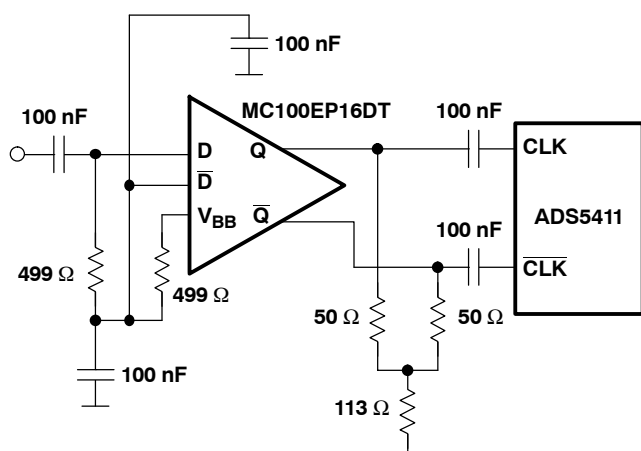


Figure 28. Differential Clock Using PECL Logic

Another possibility is the use of a logic based clock, as PECL. In this case, the slew rate of the edges will most likely be much higher than the one obtained for the same clock amplitude based on a sinusoidal clock. This solution would minimize the effect of the slope dependent ADC jitter. Nevertheless, observe that for the ADS5411, this term is small and has been optimized. Using logic gates to square a sinusoidal clock may not produce the best results as logic gates may not have been optimized to act as comparators, adding too much jitter while squaring the inputs.

The common-mode voltage of the clock inputs is set internally to 2.4 V using internal 1 kΩ resistors. It is recommended using an ac coupling, but if for any reason, this scheme is not possible, due to, for instance, asynchronous clocking, the ADS5411 presents a good tolerance to clock common-mode variation.

Additionally, the internal ADC core uses both edges of the clock for the conversion process. This means that, ideally, a 50% duty cycle should be provided.

DIGITAL OUTPUTS

The ADC provides 11 data outputs (D10 to D0, with D10 being the MSB and D0 the LSB), a data-ready signal (DRY, pin 52), and an out-of-range indicator (OVR, pin 32) that equals 1 when the output reaches the full-scale limits.

The output format is two's complement. When the input voltage is at negative full scale (around -1.1 V differential), the output will be, from MSB to LSB, 100 0000 0000. Then, as the input voltage is increased, the output switches to 100 0000 0001, 100 0000 0010 and so on until 111 1111 1111 right before mid-scale (when both inputs are tight together if we neglect offset errors). Further increase on input voltage outputs the word 000 0000 0000, to be followed by 000 0000 0001, 000 0000 0010, and so on until reaching 111 1111 1111 at full-scale input (1.1 V differential).

APPLICATION INFORMATION

Although the output circuitry of the ADS5411 has been designed to minimize the noise produced by the transients of the data switching, care must be taken when designing the circuitry reading the ADS5411 outputs. Output load capacitance should be minimized by minimizing the load on the output traces, reducing their length and the number of gates connected to them, and by the use of a series resistor with each pin. Typical numbers on the data sheet tables and graphs are obtained with 100 Ω series resistor on each digital output pin, followed by a 74AVC16244 digital buffer as the one used in the evaluation board.

POWER SUPPLIES

The use of low noise power supplies with adequate decoupling is recommended, being the linear supplies the first choice vs switched ones, which tend to generate more noise components that can be coupled to the ADS5411.

The ADS5411 uses two power supplies. For the analog portion of the design, a 5 V AV_{DD} is used, while for the digital outputs supply (DRV_{DD}), we recommend the use of 3.3 V. All the ground pins are marked as GND, although AGND pins and DRGND pins are not tied together inside the package. Customers willing to experiment with different grounding schemes should know that AGND pins are 4, 7, 10, 13, 15, 17, 19, 21, 23, 25, 27, and 29, while DRGND pins are 2, 34, and 42. Nevertheless, we recommend that both grounds are tied together externally, using a common ground plane. That is the case on the production test boards and

modules provided to customer for evaluation. In order to obtain the best performance, user should layout the board to guarantee that the digital return currents do not flow under the analog portion of the board. This can be achieved without the need to split the board and just with careful component placing and increasing the number of vias and ground planes.

Finally, notice that the metallic heat sink under the package is also connected to analog ground.

LAYOUT INFORMATION

The evaluation board represents a good guideline of how to layout the board to obtain the maximum performance out of the ADS5411. General design rules as the use of multilayer boards, single ground plane for both, analog and digital ADC ground connections and local decoupling ceramic chip capacitors should be applied. The input traces should be isolated from any external source of interference or noise, including the digital outputs as well as the clock traces. Clock should also be isolated from other signals, especially on applications where low jitter is required, as high IF sampling.

Besides performance oriented rules, special care has to be taken when considering the heat dissipation out of the device. The thermal heat sink (octagonal, with 2,5 mm on each side) should be soldered to the board, and provision for more than 16 ground vias should be made. The thermal package information describes the T_{JA} values obtained on the different configurations.

TAPE AND REEL INFORMATION



*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|--------------|--------------|-----------------|------|------|--------------------|--------------------|---------|---------|---------|---------|--------|---------------|
| ADS5411IPJYR | QFP | PJY | 52 | 1000 | 330.0 | 24.4 | 12.3 | 12.3 | 2.5 | 16.0 | 24.0 | Q2 |

TAPE AND REEL BOX DIMENSIONS

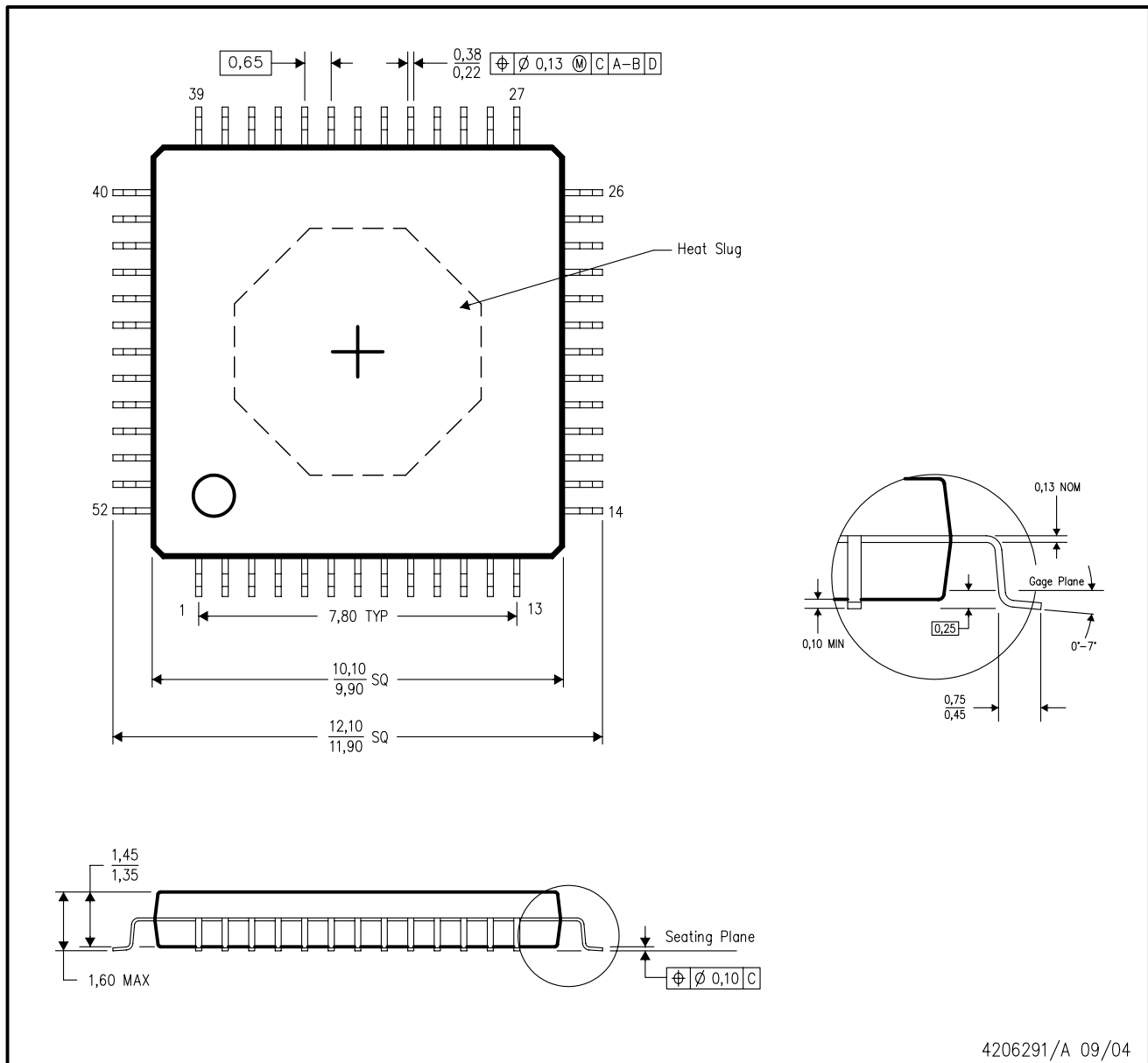


*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|--------------|--------------|-----------------|------|------|-------------|------------|-------------|
| ADS5411IPJYR | QFP | PJY | 52 | 1000 | 346.0 | 346.0 | 41.0 |

PJY (S-PQFP-G52)

PLASTIC QUAD FLATPACK



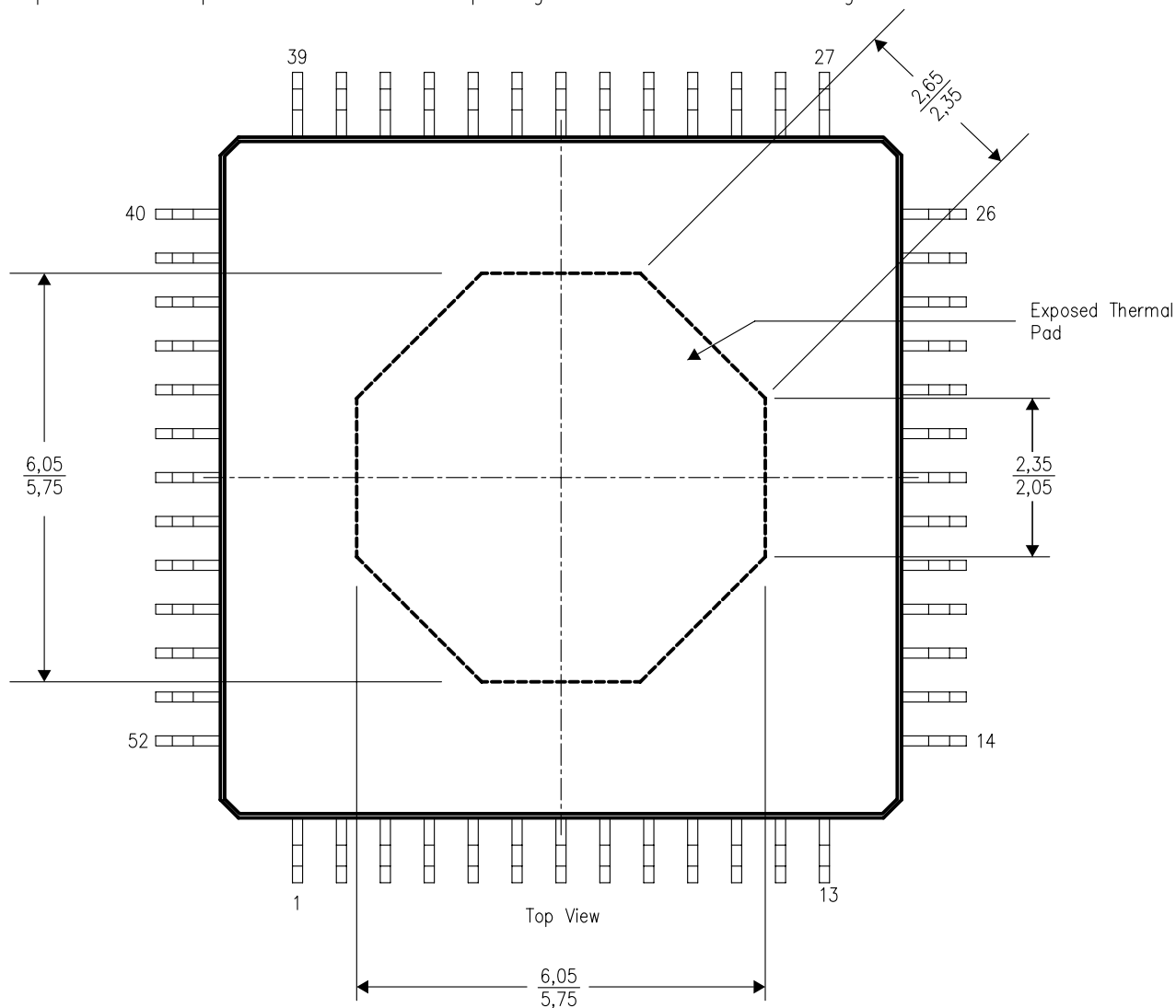
- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold flash or protrusion.
 - D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com.

THERMAL INFORMATION

This PowerQuad 4™ package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For additional information on the PowerQuad 4 package and how to take advantage of its heat dissipating abilities, refer to Technical Brief, PowerPAD Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 and Application Brief, PowerPAD Made Easy, Texas Instruments Literature No. SLMA004. Both documents are available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

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